

B mobile HK Limited

SMART PHONE

Model: AX540
Serial Model: N/A

April 28, 2013




Report No.: 13050012-FCC-E

(This report supersedes NONE)



Modifications made to the product : None

This Test Report is Issued Under the Authority of:

		
William Long Compliance Engineer	Alex Liu Technical Manager	

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Test result presented in this test report is applicable to the representative sample only.

EMC Test Report

To: FCC Part 15 Subpart B Class B: 2012, ANSI C63.4: 2009

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Country/Region	Accreditation Body	Scope
USA	FCC, A2LA	EMC , RF/Wireless , Telecom
Canada	IC, A2LA, NIST	EMC, RF/Wireless , Telecom
Taiwan	BSMI , NCC , NIST	EMC, RF, Telecom , Safety
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Accreditations for Product Certifications

Country/Region	Accreditation Body	Scope
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Canada	IC FCB , NIST	EMC , RF , Telecom
Singapore	iDA, NIST	EMC , RF , Telecom
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1 EXECUTIVE SUMMARY & EUT INFORMATION

The purpose of this test programme was to demonstrate compliance of the B mobile HK Limited, SMART PHONE and Model: AX540 against the current Stipulated Standards. The SMART PHONE has demonstrated compliance with the FCC Part 15 Subpart B Class B: 2012, ANSI C63.4: 2009.

EUT Information

EUT Description : SMART PHONE

Main Model : AX540

Serial Model : N/A

Antenna Gain : UMTS-FDD Band V/GSM850: -1.7 dBi
UMTS-FDD Band II/PCS1900: -1.2 dBi
Bluetooth: -2.2 dBi
WIFI: -2.2 dBi

Input Power : Li-ion Rechargeable Battery
Model: BT-1500-252
Capacity: 1500mAh
Nominal Voltage: 3.7V
Charging Voltage Limit: 4.2V

Classification Per Stipulated Test Standard : Class B Emission Product Per
FCC Part 15 Subpart B Class B: 2012, ANSI C63.4: 2009



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2 TECHNICAL DETAILS

Purpose	Compliance testing of SMART PHONE with stipulated standards
Applicant / Client	B mobile HK Limited Ground floor, 144 Un Chau Street, Sham Shui Po, Hong Kong
Manufacturer	SHENZHEN MALATA MOBILE COMMUNICATION CO.,LTD. 25/F,Malata Technology Building,NO.9998 Shennan Rd,Hi-tech Park,Nanshan,Shenzhen,P.R. China
Laboratory performing the tests	SIEMIC Nanjing (China) Laboratories NO.2-1, Longcang Dadao, Yuhua Economic Development Zone, Nanjing, China Tel:+86(25)86730128/86730129 Fax:+86(25)86730127 Email:info@siemic.com
Test report reference number	13050012-FCC-E
Date EUT received	April 15, 2013
Standard applied	FCC Part 15 Subpart B Class B: 2012, ANSI C63.4: 2009
Dates of test (from – to)	April 27, 2013
No of Units	#1
Equipment Category	JBP
Trade Name	B mobile
RF Operating Frequency (ies)	GSM850 TX : 824.2 ~ 848.8 MHz; RX : 869.2 ~ 893.8 MHz PCS1900 TX : 1850.2 ~ 1909.8 MHz; RX : 1930.2 ~ 1989.8 MHz UMTS-FDD Band V TX : 826.4 ~ 846.6 MHz; RX : 871.4 ~ 891.6 MHz UMTS-FDD Band II TX :1852.4 ~ 1907.6 MHz; RX : 1932.4 ~ 1987.6 MHz 802.11b/g/n: 2412-2462 MHz Bluetooth : 2402-2480 MHz
Number of Channels	299CH (PCS1900) and 124CH (GSM850) UMTS-FDD Band V: 102CH UMTS-FDD Band II: 277CH Bluetooth: 79CH 802.11b/g/n: 11CH
Modulation	GSM / GPRS: GMSK UMTS-FDD: QPSK 802.11b/g/n: DSSS/OFDM Bluetooth: GFSK
GPRS Multi-slot class	8/10/12
FCC ID	ZSW-AX540



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3 MODIFICATION

NONE



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4 TEST SUMMARY

The product was tested in accordance with the following specifications.
All testing has been performed according to below product classification:

Class B Emission Product

Test Results Summary

Emissions			
Test Standard	Description	Product Class	Pass / Fail
FCC Part 15 Subpart B Class B: 2012, ANSI C63.4: 2009	Conducted Emissions	See Above	Pass
FCC Part 15 Subpart B Class B: 2012, ANSI C63.4: 2009	Radiated Emissions	See Above	Pass

All measurement uncertainty is not taken into consideration for all presented test result.



5 MEASUREMENTS, EXAMINATION AND DERIVED RESULTS

5.1 Conducted Emissions Test Result

Note:

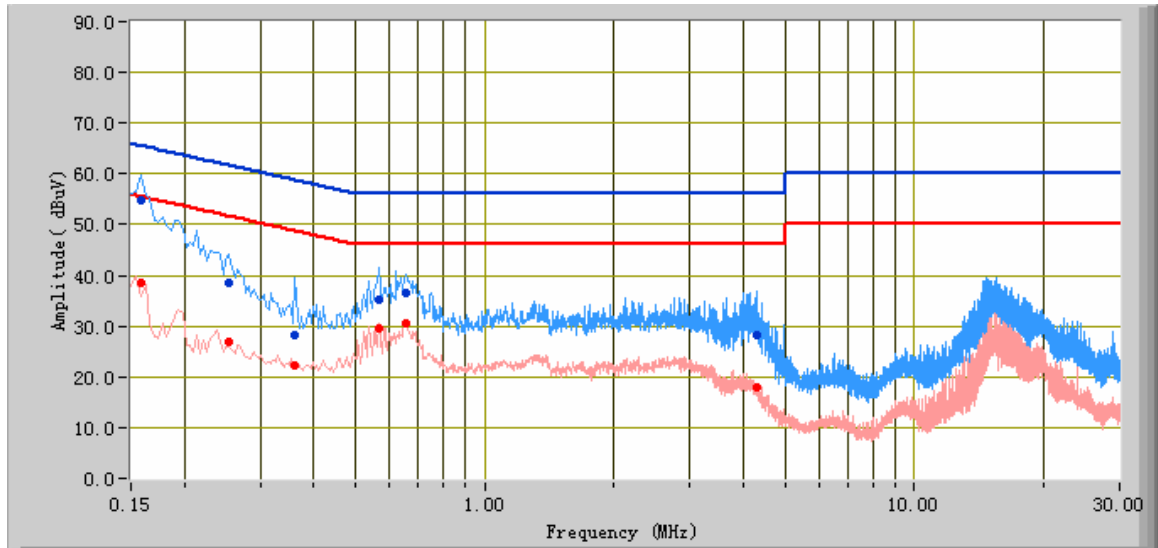
1. All possible modes of operation were investigated. Only the several worst case emissions measured, using the correct CISPR and Average detectors, are reported. All other emissions were relatively insignificant.
2. A "-ve" margin indicates a PASS as it refers to the margin present below the limit line at the particular frequency.
3. Conducted Emissions Measurement Uncertainty
All test measurements carried out are traceable to national standards. The uncertainty of the measurement at a confidence level of approximately 95% (in the case where distributions are normal), with a coverage factor of 2, in the range 9kHz – 30MHz (Average & Quasi-peak) is $\pm 3.86\text{dB}$.
4. Environmental Conditions

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1009mbar
5. Test date : April 27, 2013
Tested By : William Long

Test Result: Pass

Test Mode:	Charging & Downloading
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Peak Detector		Quasi Peak Limit	
Average Detector		Average Limit	



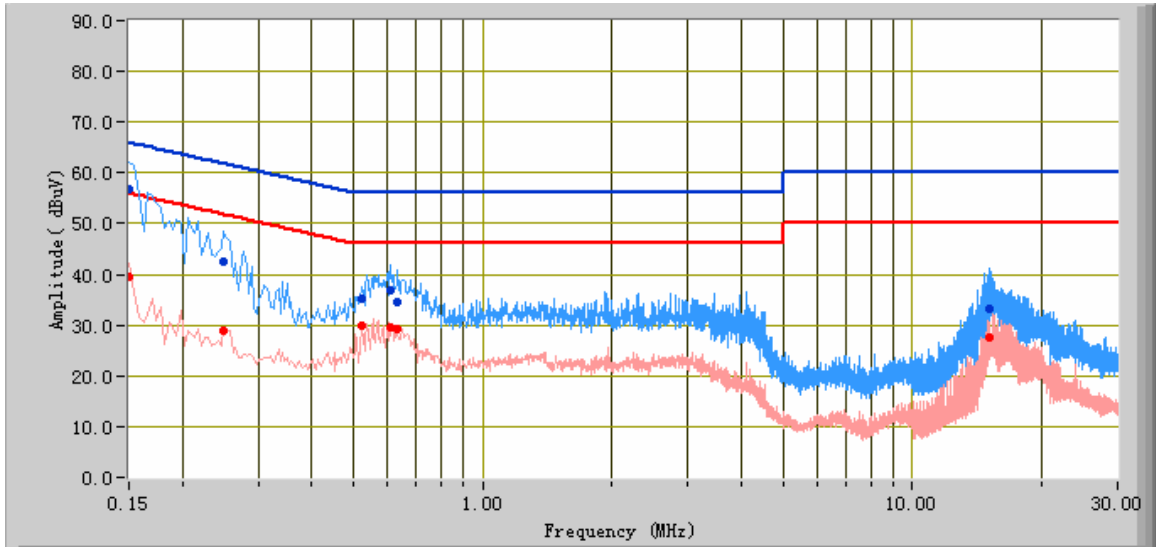
Test Data

Phase Neutral Plot at 120V AC, 60Hz

Frequency (MHz)	Peak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Average (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Factors (dB)
0.16	54.90	65.57	-10.67	38.39	55.57	-17.18	12.10
0.57	35.21	56.00	-20.79	29.71	46.00	-16.29	11.01
0.65	36.56	56.00	-19.44	30.70	46.00	-15.30	10.95
0.25	38.47	61.62	-23.16	26.75	51.62	-24.87	11.45
4.28	28.22	56.00	-27.78	17.92	46.00	-28.08	10.94
0.36	28.26	58.68	-30.42	22.21	48.68	-26.47	11.28

Test Mode:	Charging & Downloading
-------------------	-----------------------------------

Peak Detector  **Quasi Peak Limit** 
Average Detector  **Average Limit** 





Test Data

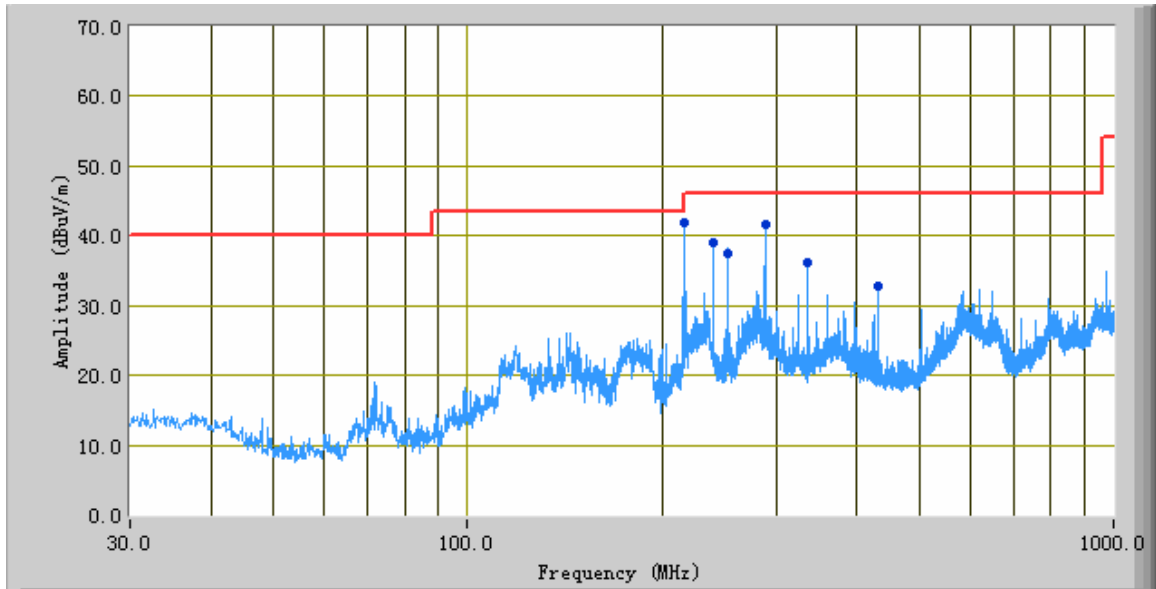
Phase Line Plot at 120V AC, 60Hz

Frequency (MHz)	Peak (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Average (dBµV/m)	Limit (dBµV/m)	Margin (dB)	Factors (dB)
0.15	56.84	66.00	-9.16	39.65	56.00	-16.35	12.22
0.25	42.60	61.76	-19.16	28.95	51.76	-22.81	11.45
0.61	36.94	56.00	-19.06	29.43	46.00	-16.57	11.00
0.63	34.63	56.00	-21.37	29.13	46.00	-16.87	10.98
0.52	35.06	56.00	-20.94	29.97	46.00	-16.03	11.07
15.09	33.15	60.00	-26.85	27.47	50.00	-22.53	11.41

Test Mode: Charging & Downloading

Below 1GHz

Peak Detector 
 Quasi Peak Limit 



Test Data

Vertical & Horizontal Polarity Plot at 3m

Frequency (MHz)	Quasi Peak (dBμV/m)	Azimuth	Polarity (H/V)	Height (cm)	Factors (dB)	Limit (dBμV/m)	Margin (dB)
216.41	41.96	255.00	H	142.00	-31.53	46.00	-4.04
288.56	41.75	253.00	V	104.00	-29.66	46.00	-4.25
239.99	39.10	256.00	H	120.00	-30.40	46.00	-6.90
252.48	37.38	248.00	H	128.00	-30.21	46.00	-8.62
335.99	36.18	307.00	H	100.00	-30.81	46.00	-9.82
432.86	32.81	67.00	H	105.00	-28.77	46.00	-13.19

Note: The data above 1 GHz which below 20 dB to the limit was not recorded.



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Annex A. TEST INSTRUMENTATION & GENERAL PROCEDURES

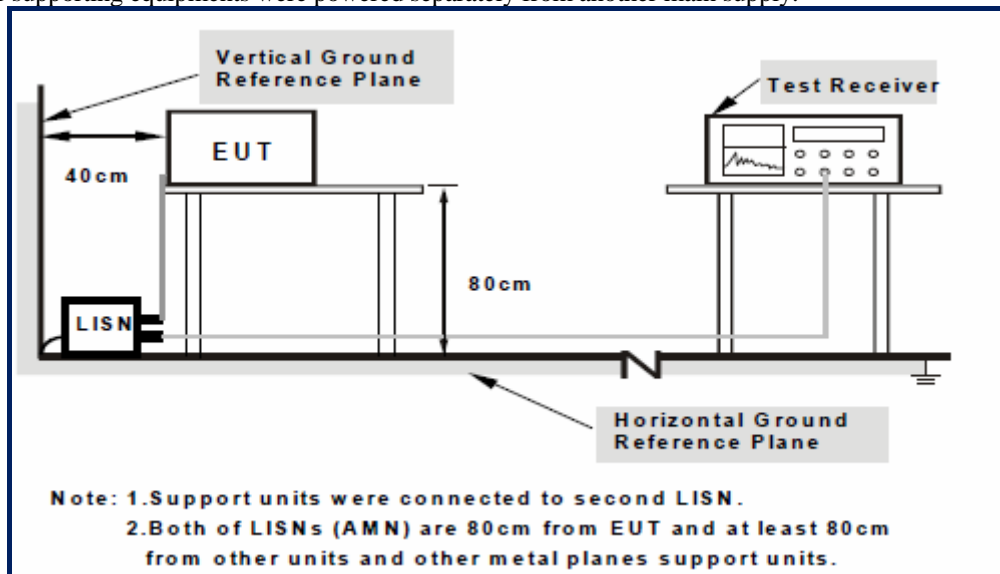
Annex A.i. TEST INSTRUMENTATION

Instrument	Model	Serial #	Calibration Date	Calibration Due Date
AC Line Conducted Emissions				
R&S EMI Test Receiver	ESPI3	101216	10/27/2012	10/26/2013
ROHDE&SCHWARZ V-LISN	ESH3-Z5	838979/005	10/27/2012	10/26/2013
Com-Power Transient Limiter	LIT-153	531021	11/03/2012	11/02/2013
SIEMIC Labview Conducted Emissions software	V1.0	N/A	N/A	N/A
Radiated Emissions				
Hp Spectrum Analyzer	8563E	3821A09023	01/10/2013	01/09/2014
R&S EMI Receiver	ESPI3	101216	10/27/2012	10/26/2013
Antenna (30MHz~6GHz)	JB6	A121411	03/27/2013	03/26/2014
ETS-Lindgren Antenna (1 ~18GHz)	3115	N/A	10/29/2012	10/28/2013
A-INFOMW Antenna (1 ~18GHz)	JXTXLB-10180	J2031081120092	06/25/2012	06/24/2013
Horn Antenna (18~40GHz)	AH-840	101013	04/22/2013	04/22/2014
Microwave Pre-Amp (18~40GHz)	PA-840	181250	05/30/2012	05/29/2013
Hp Agilent Pre-Amplifier	8447F	1937A01160	11/03/2012	11/02/2013
MITEQ Pre-Amplifier (0.1 ~ 18GHz)	AMF-7D-00101800-30-10P	1451709	11/03/2012	11/02/2013
Chamber	3m	N/A	04/13/2013	04/12/2014
SIEMIC Labview Radiated Emissions software	V1.0	N/A	N/A	N/A

Annex A.ii. AC LINE CONDUCTED EMISSIONS TEST DESCRIPTION

Test Set-up

1. The EUT and supporting equipment were set up in accordance with the requirements of the standard on top of a 1.5m x 1m x 0.8m high, non-metallic table, as shown in Annex B.
2. The power supply for the EUT was fed through a 50Ω/50μH EUT LISN, connected to filtered mains.
3. The RF OUT of the EUT LISN was connected to the EMI test receiver via a low-loss coaxial cable.
4. All other supporting equipments were powered separately from another main supply.



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration1

Test Method

1. The EUT was switched on and allowed to warm up to its normal operating condition.
2. A scan was made on the NEUTRAL line (for AC mains) or Earth line (for DC power) over the required frequency range using an EMI test receiver.
3. High peaks, relative to the limit line, were then selected.
4. The EMI test receiver was then tuned to the selected frequencies and the necessary measurements made with a receiver bandwidth setting of 10 kHz. For FCC tests, only Quasi-peak measurements were made; while for CISPR/EN tests, both Quasi-peak and Average measurements were made.
5. Steps 2 to 4 were then repeated for the LIVE line (for AC mains) or DC line (for DC power).

Description of Conducted Emission Program

This EMC Measurement software run LabView automation software and offers a common user interface for electromagnetic interference (EMI) measurements. This software is a modern and powerful tool for controlling and monitoring EMI test receivers and EMC test systems. It guarantees reliable collection, evaluation, and documentation of measurement results. Basically, this program will run a pre-scan measurement before it proceeds with the final measurement. The pre-scan routine will run the common scan range from 150 kHz to 30 MHz; the program will first start a peak and average scan on selectable measurement time and step size. After the program complete the pre-scan, this program will perform the Quasi Peak and Average measurement, based on the pre-scan peak data reduction result.



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Sample Calculation Example

At 20 MHz

limit = $250 \mu\text{V} = 47.96 \text{ dB}\mu\text{V}$

Transducer factor of LISN, pulse limiter & cable loss at 20 MHz = 11.20 dB

Q-P reading obtained directly from EMI Receiver = 40.00 dB μV
(Calibrated for system losses)

Therefore, Q-P margin = $47.96 - 40.00 = 7.96$ i.e. **7.96 dB below limit**

Annex A. iii. RADIATED EMISSIONS TEST DESCRIPTION

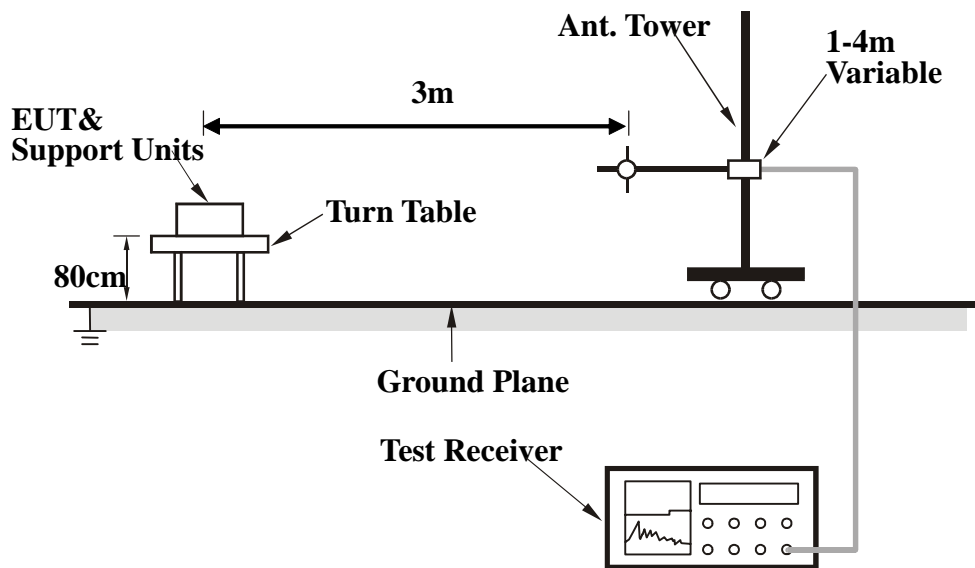
EUT Characterisation

EUT characterisation, over the frequency range from 30MHz to 10th Harmonic, was done in order to minimise radiated emissions testing time while still maintaining high confidence in the test results.

The EUT was placed in the chamber, at a height of about 0.8 m on a turntable. Its radiated emissions frequency profile was observed, using a spectrum analyzer /receiver with the appropriate broadband antenna placed 3m away from the EUT. Radiated emissions from the EUT were maximised by rotating the turntable manually, changing the antenna polarisation and manipulating the EUT cables while observing the frequency profile on the spectrum analyzer / receiver. Frequency points at which maximum emissions occurred; clock frequencies and operating frequencies were then noted for the formal radiated emissions test at the Open Area Test Site (OATS) or 3m EMC chamber.

Test Set-up

1. The EUT and supporting equipment were set up in accordance with the requirements of the standard on top of a 1.5mX1.0mX0.8m high, non-conductive table.
2. The filtered power supply for the EUT and supporting equipment were tapped from the appropriate power sockets located on the turntable.
3. The relevant broadband antenna was set at the required test distance away from the EUT and supporting equipment boundary.



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration2

Test Method

The following procedure was performed to determine the maximum emission axis of EUT:

1. With the receiving antenna is H polarization, rotate the EUT in turns with three orthogonal axes to determine the axis of maximum emission.
2. With the receiving antenna is V polarization, rotate the EUT in turns with three orthogonal axes to determine the axis of maximum emission.
3. Compare the results derived from above two steps. So, the axis of maximum emission from EUT was determined and the configuration was used to perform the final measurement.

Final Radiated Emission Measurement

1. Setup the configuration according to figure 1. Turn on EUT and make sure that it is in normal function.
2. For emission frequencies measured below 1GHz, a pre-scan is performed in a shielded chamber to determine the accurate frequencies of higher emissions will be checked on an open test site. As the same purpose, for emission frequencies measured above 1GHz, a pre-scan also be performed with a 1 meter measuring distance before final test.
3. For emission frequencies measured below and above 1GHz, set the spectrum analyzer on a 100kHz and 1MHz resolution bandwidth respectively for each frequency measured in step 2.
4. The search antenna is to be raised and lowered over a range from 1 to 4 meters in horizontally polarized orientation. Position the highness when the highest value is indicated on spectrum analyzer, then change the orientation of EUT on test table over a range from 0° to 360° with a speed as slow as possible, and keep the azimuth that highest emission is indicated on the spectrum analyzer. Vary the antenna position again and record the highest value as a final reading.
5. Repeat step 4 until all frequencies need to be measured was complete.
6. Repeat step 5 with search antenna in vertical polarized orientations.

During the radiated emission test, the Spectrum Analyzer was set with the following configurations:

Frequency Band (MHz)	Function	Resolution bandwidth	Video Bandwidth
30 to 1000	Peak	100kHz	100kHz
Above 1000	Peak	1MHz	1MHz
	Average	1MHz	10Hz

Sample Calculation Example

The field strength is calculated by adding the Antenna Factor and Cable Factor, and subtracting the Amplifier Gain (if any) from the measured reading. For the limit is employed average value, therefore the peak value can be transferred to average value by subtracting the duty factor. The basic equation with a sample calculation is as follows:

$$\text{Peak} = \text{Reading} + \text{Corrected Factor}$$

where

Corr. Factor = Antenna Factor + Cable Factor - Amplifier Gain (if any)

And the average value is

$$\text{Average} = \text{Peak Value} + \text{Duty Factor or}$$

$$\text{Set RBW} = 1\text{MHz, VBW} = 10\text{Hz.}$$

Note:

If the measured frequencies are fall in the restricted frequency band, the limit employed must be quasi peak value when frequencies are below or equal to 1GHz. And the measuring instrument is set to quasi peak detector function.



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Annex B. EUT AND TEST SETUP PHOTOGRAPHS

Annex B.i. Photograph 1: EUT External Photo



Whole Package - Top View



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EUT - Front View



EUT - Rear View



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EUT - Top View



EUT - Bottom View

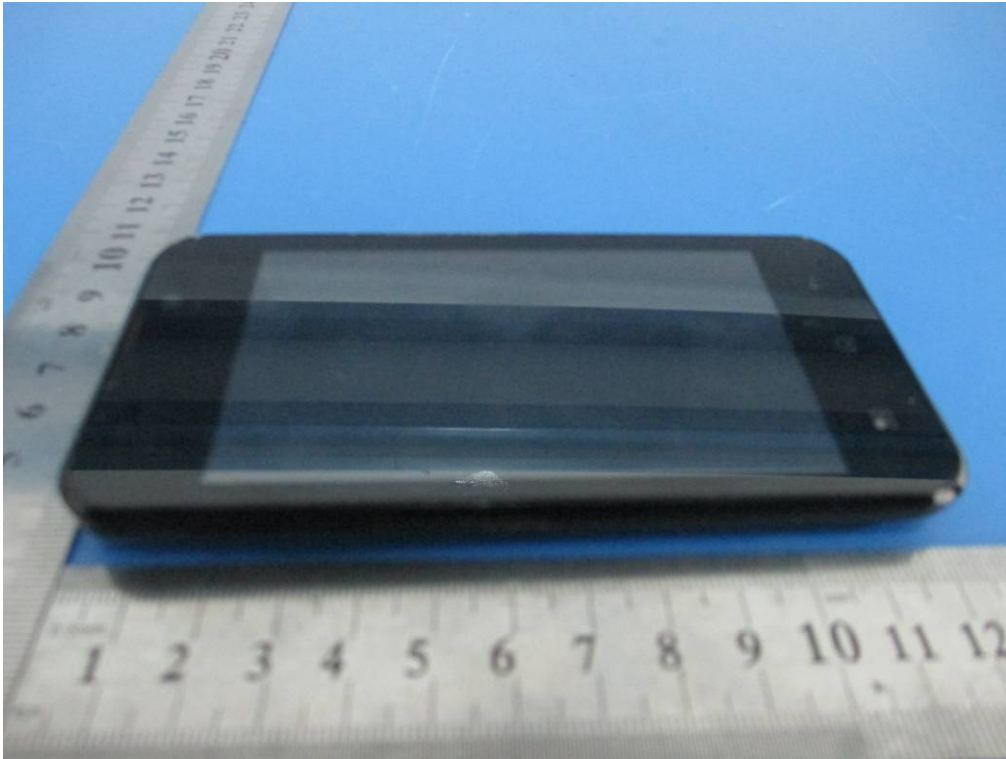


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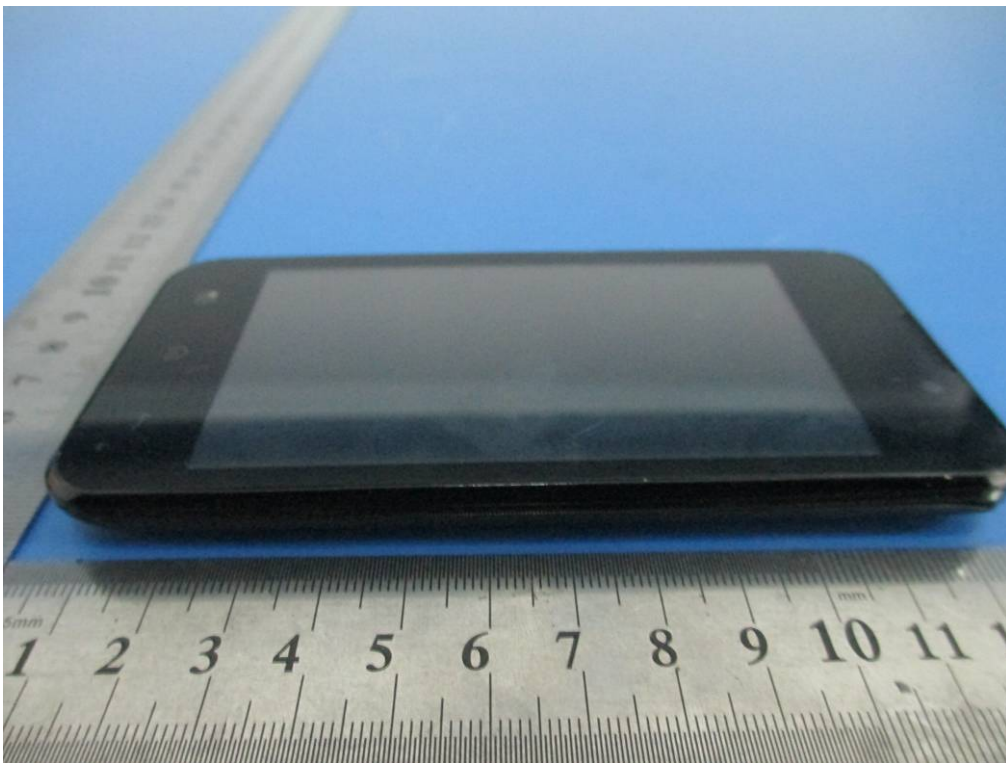
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EUT - Left View



EUT - Right View



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Annex B.ii. Photograph 2: EUT Internal Photo



Cover Off - Top View 1



Cover Off - Bottom View



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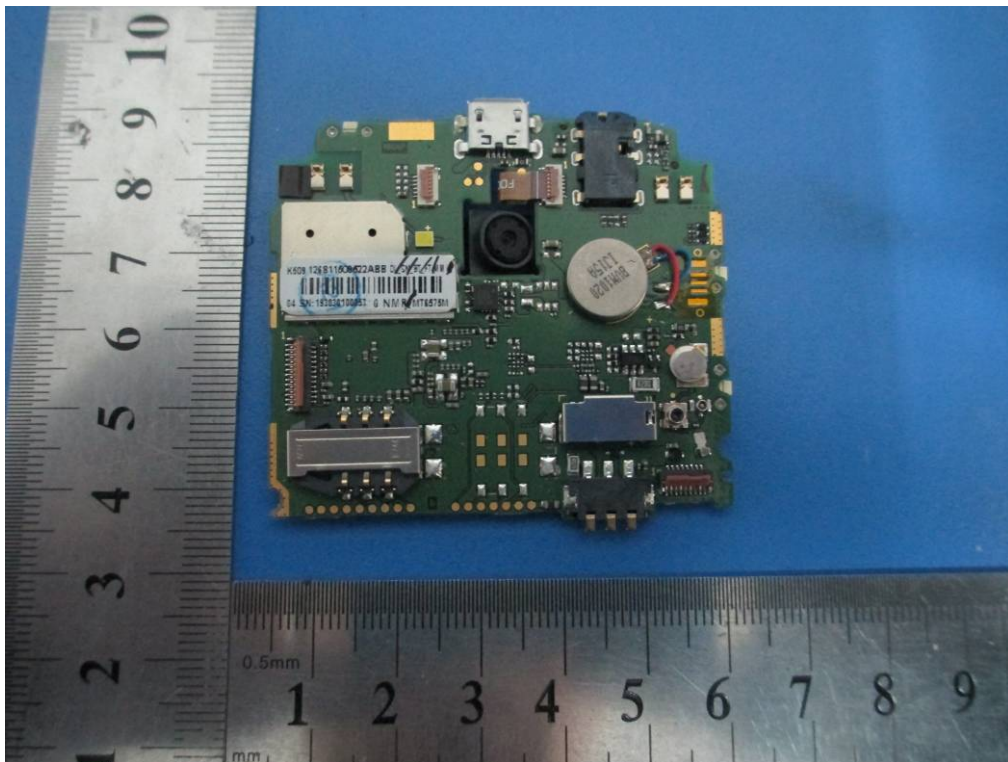
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Bottom View – PCB 1#



Top - PCB 1#

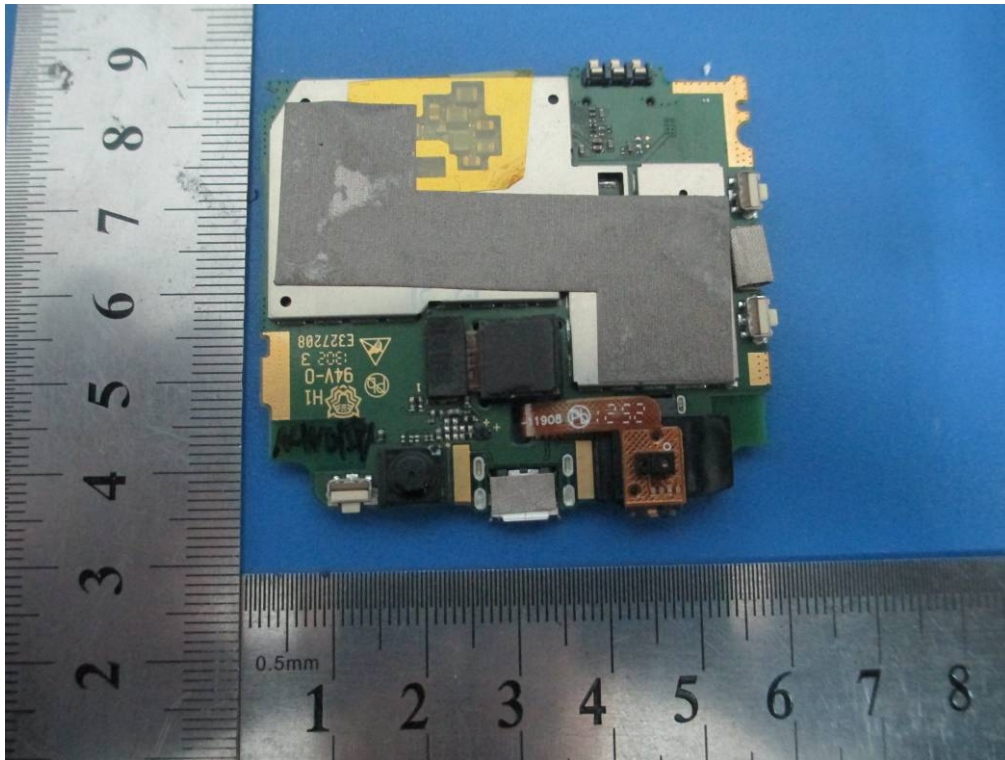


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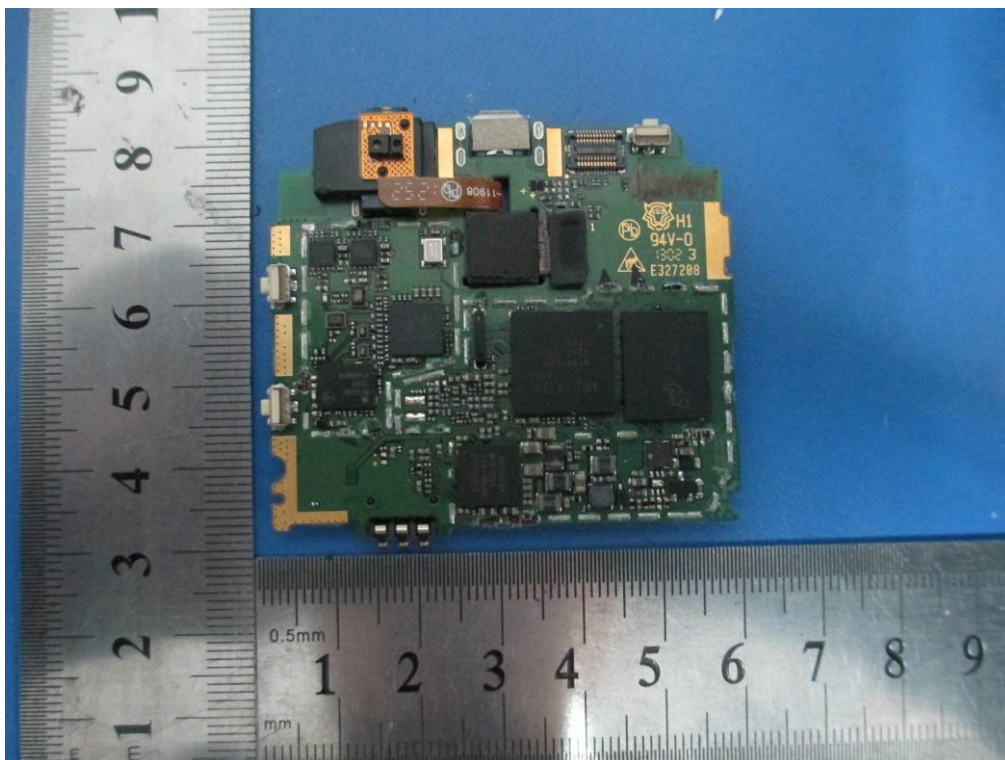
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Bottom – PCB 1#



Uncover Without Shielding - Top View PCB 1#

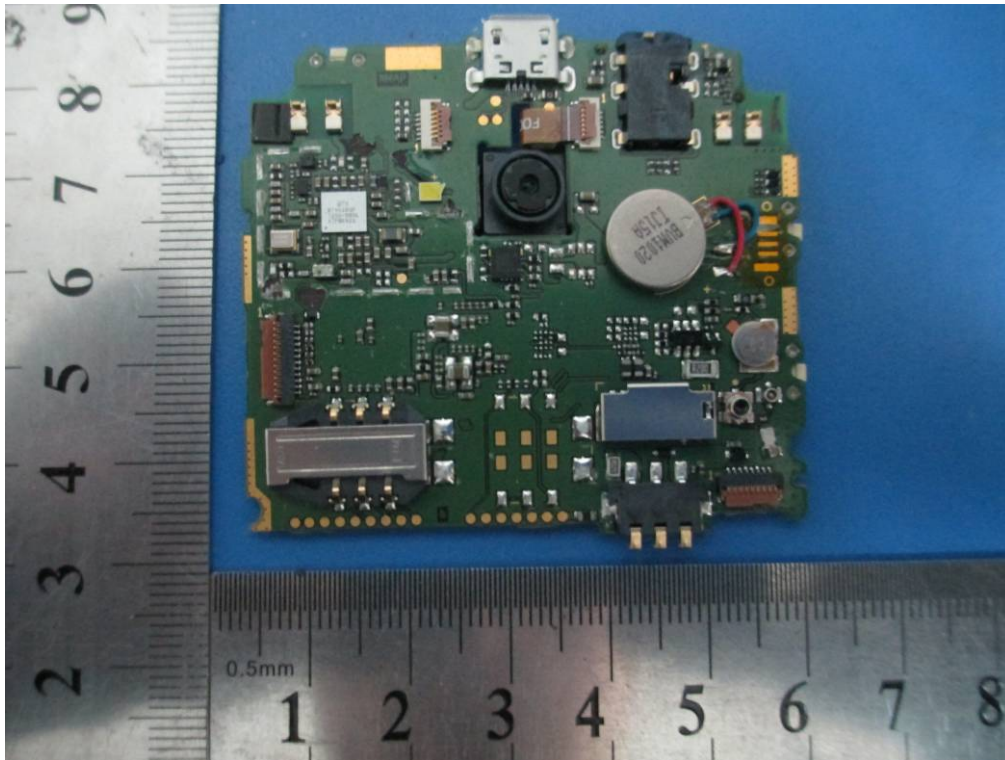


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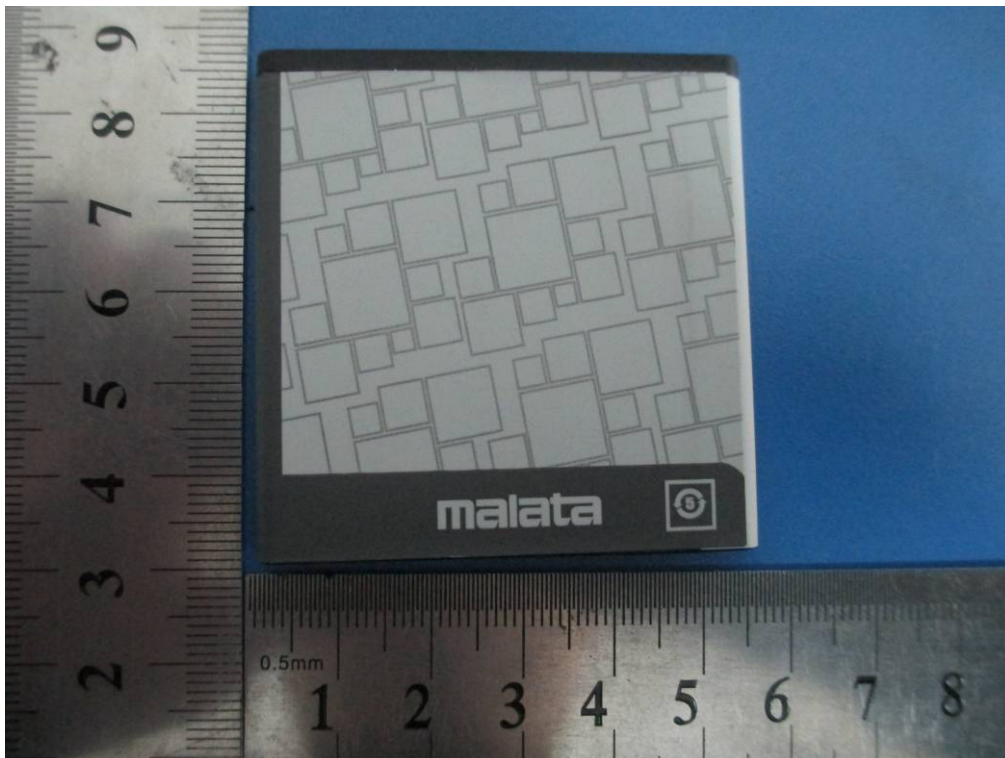
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Uncover Without Shielding - Bottom View PCB 1#



Battery - Top View



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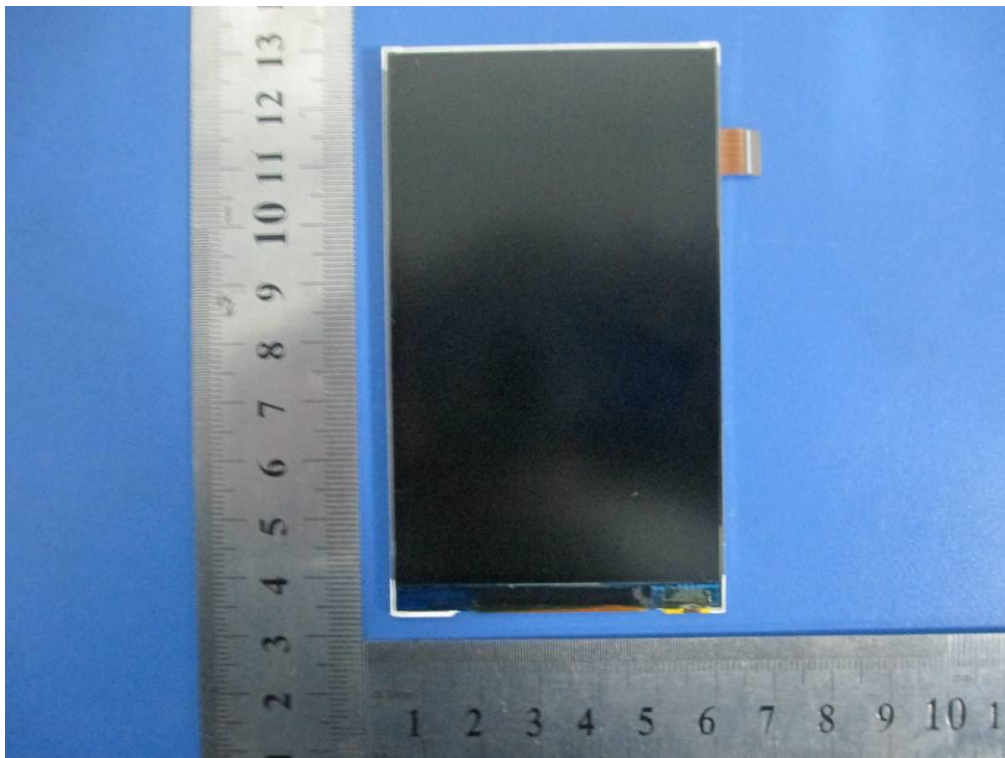
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Battery - Bottom View



LCD - Top View

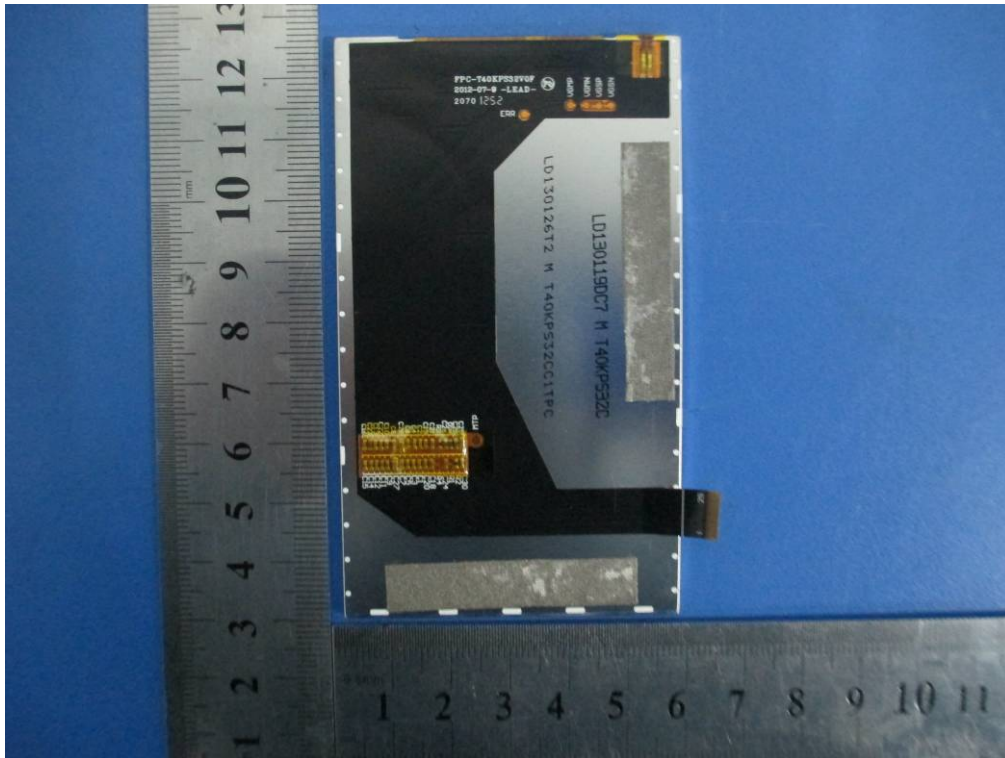


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LCD - Bottom View



Bluetooth /WIFI Antenna

GSM Antenna

Antenna



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Uncover LCD - Top View



Uncover LCD - Top View



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Annex B.iii. Photograph 3: Test Setup Photo



Conducted Emissions Test Setup Front View



Conducted Emissions Test Setup Side View

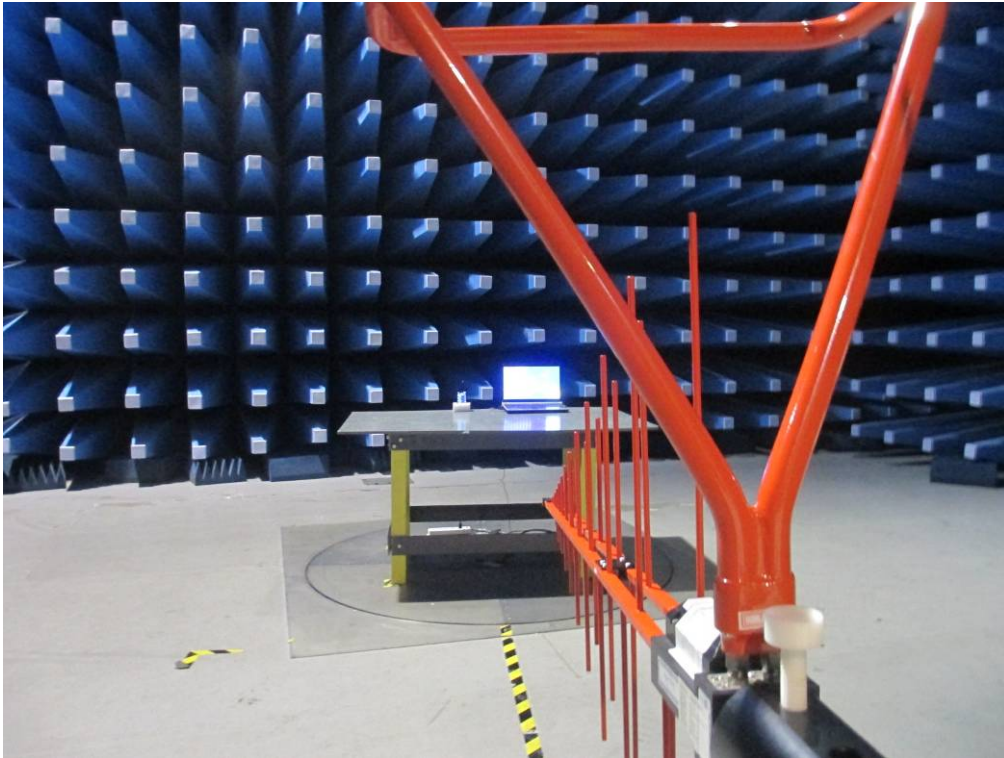


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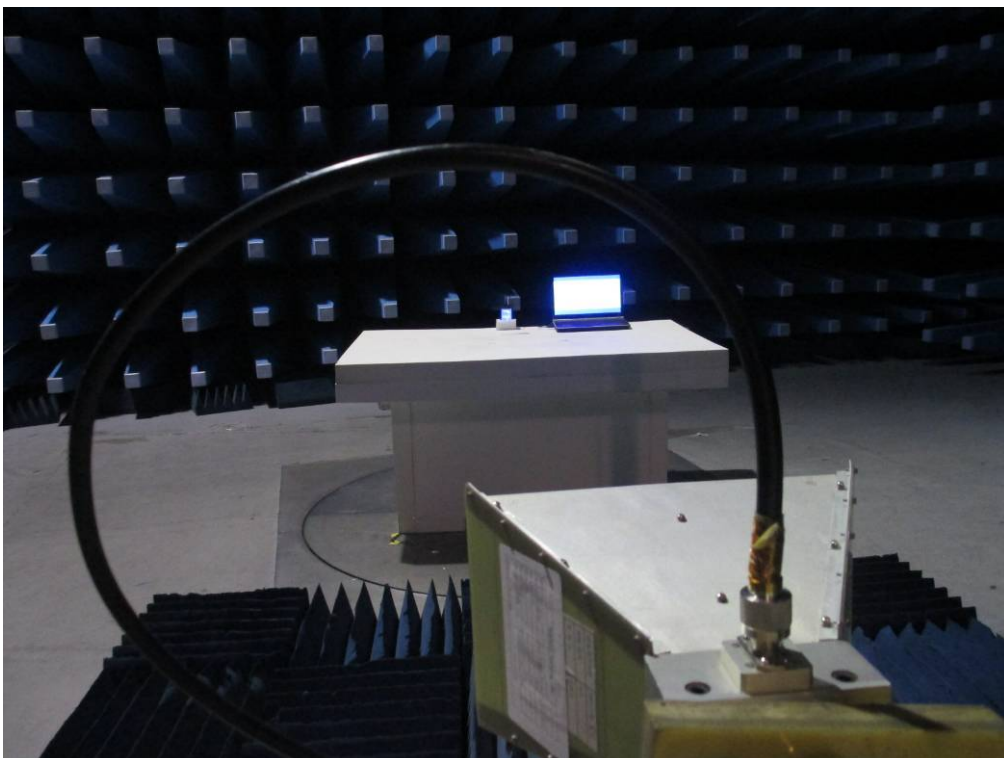
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Radiated Spurious Emissions Test Setup Below 1GHz - Front View



Radiated Spurious Emissions Test Setup Above 1GHz -Front View



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Annex C. TEST SETUP AND SUPPORTING EQUIPMENT

EUT TEST CONDITIONS

Annex C. i. SUPPORTING EQUIPMENT DESCRIPTION

The following is a description of supporting equipment and details of cables used with the EUT.

Equipment Description (Including Brand Name)	Model & Serial Number	Cable Description (List Length, Type & Purpose)
Gateway Laptop	MS2288 & LXWHF02013951C3CA92200	N/A



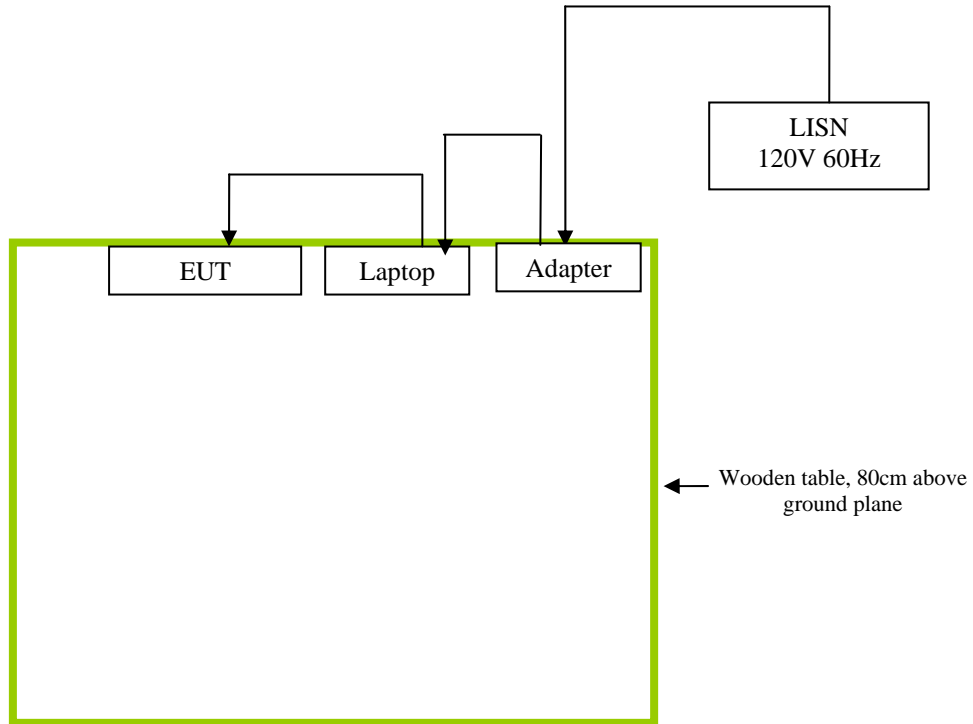
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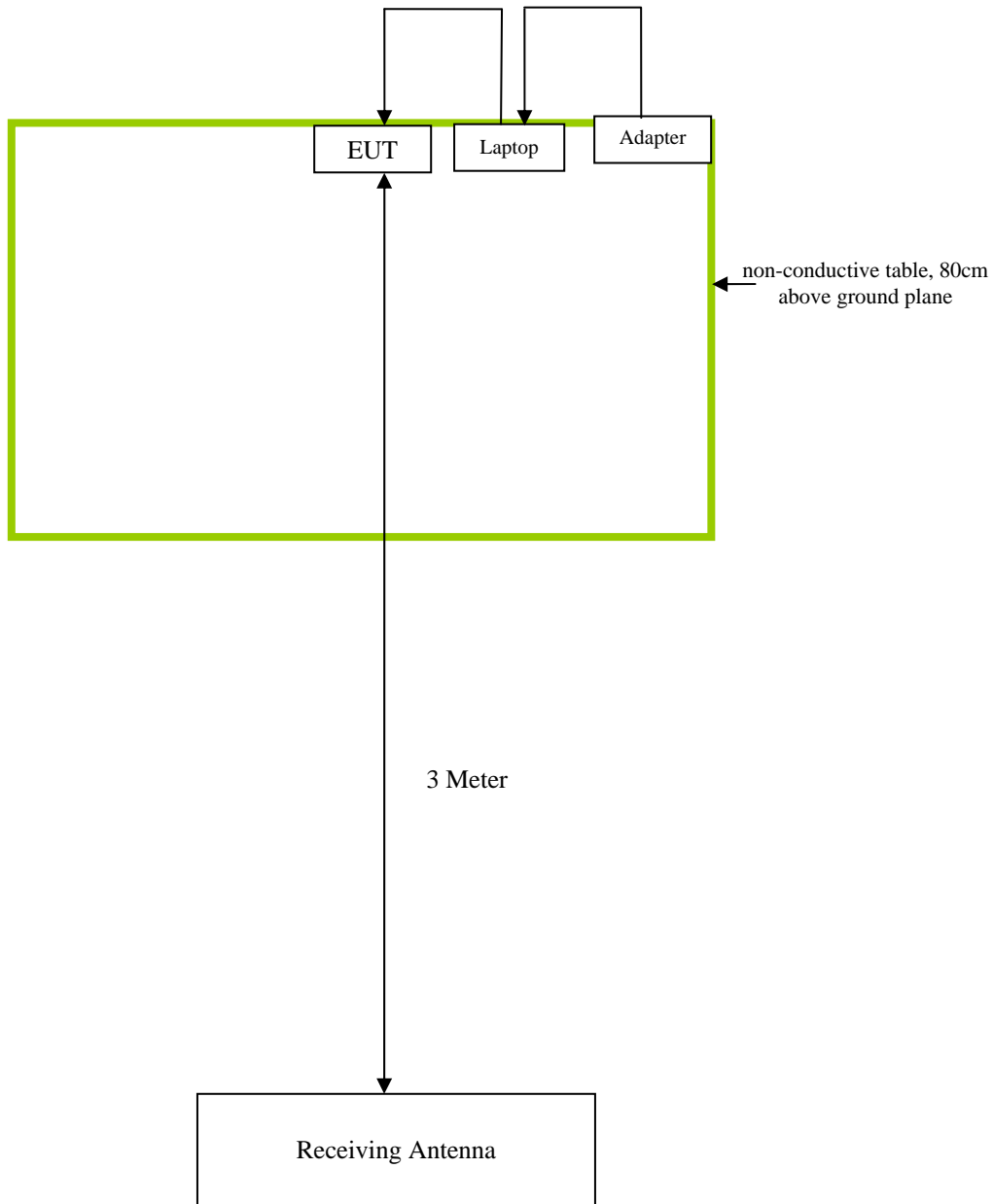
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Block Configuration Diagram for Conducted Emissions Mode: Charging & Downloading





Block Configuration Diagram for Radiated Emissions Mode: Charging & Downloading





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Annex C.ii. EUT OPERATING CONDITIONS

The following is the description of how the EUT is exercised during testing.

Test	Description Of Operation
Emissions	Charging & Downloading



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Annex D. USER MANUAL / BLOCK DIAGRAM / SCHEMATICS / PART LIST

Please see attachment



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Annex E. DECLARATION OF SIMILARITY

N/A